

SECUTEST ST BASE(10) / PRO and SECULIFE ST BASE(25)

Testers for Testing the Electrical Safety of Devices per VDE 0701-0702, IEC 62353 and IEC 60974-4

3-447-066-03 2/10.20

Do



the full operating instructions!

Operating and Connection Overview



Note 😥

Features such as touchscreen, Bluetooth® etc. can be found in your instrument's data sheet.

Tabl	Table of ContentsPage		
1	Safety Precautions4		
2	Scope of Delivery6		
3	Initial Start-Up7		
3.1	Mains Connection7		
3.2	Detection of Mains Connection Errors7		
4	Overview of Functions of the Testers8		
5	User Interface Symbols – Parameter and Softkey Symbols10		
6	Internal Database11		
6.1	Creation of Test Structures11		
6.2	Export – Transmission and Storage of Test		
	Structures and Measurement Data11		
6.3	Import (PRO and/or Feature KB01 only)11		
7	Data Input12		
7.1	Keyboard or Softkey Entries12		
7.2	Entry via Touch Screen (SECUTEST ST PRO		
8	Notes on Saving Single Measurements		
0	Single Measurements 14		
9 9 1	Single Measurements		
9 9.1	Single Measurements14 RPE – Protective Conductor Resistance for Protection Class I Devices		
9 9.1 9.2	Single Measurements		
9 9.1 9.2	Single Measurements14RPE – Protective Conductor Resistance forProtection Class I DevicesRINS – Insulation Resistance Measurementfor Protection Class I Devicesfor Protection Class I Devices		
9 9.1 9.2 9.3	Single Measurements		
9 9.1 9.2 9.3	Single Measurements		
 9 9.1 9.2 9.3 9.4 	Single Measurements		
 9 9.1 9.2 9.3 9.4 9.5 2 	Single Measurements 14 RPE – Protective Conductor Resistance for 15 Protection Class I Devices 15 RINS – Insulation Resistance Measurement 16 for Protection Class I Devices 16 RINS – Insulation Resistance Measurement 17 for Protection Class II Devices 17 IPE – Protective Conductor Current 18 IT – Touch Current 19		
 9 9.1 9.2 9.3 9.4 9.5 9.6 9.7 	Single Measurements 14 RPE – Protective Conductor Resistance for Protection Class I Devices 15 RINS – Insulation Resistance Measurement 16 for Protection Class I Devices 16 RINS – Insulation Resistance Measurement 17 for Protection Class I Devices 17 IPE – Protective Conductor Current 18 IT – Touch Current 19 IE – Device Leakage Current 20		
 9 9.1 9.2 9.3 9.4 9.5 9.6 9.7 	Single Measurements 14 RPE – Protective Conductor Resistance for 15 Protection Class I Devices 15 RINS – Insulation Resistance Measurement 16 for Protection Class I Devices 16 RINS – Insulation Resistance Measurement 17 for Protection Class I Devices 17 IPE – Protective Conductor Current 18 IT – Touch Current 19 IE – Device Leakage Current from the Application Part Part 21		
 9 9.1 9.2 9.3 9.4 9.5 9.6 9.7 9.8 	Single Measurements 14 RPE – Protective Conductor Resistance for 15 Protection Class I Devices 15 RINS – Insulation Resistance Measurement 16 for Protection Class I Devices 16 RINS – Insulation Resistance Measurement 17 for Protection Class I Devices 17 IPE – Protective Conductor Current 18 IT – Touch Current 19 IE – Device Leakage Current from the Application Part 21 IP – Patient Leakage Current 22		
 9 9.1 9.2 9.3 9.4 9.5 9.6 9.7 9.8 9.9 	Single Measurements 14 RPE – Protective Conductor Resistance for 15 Protection Class I Devices 15 RINS – Insulation Resistance Measurement 16 for Protection Class I Devices 16 RINS – Insulation Resistance Measurement 17 for Protection Class I Devices 17 IPE – Protective Conductor Current 18 IT – Touch Current 19 IE – Device Leakage Current 20 IA – Leakage Current from the Application Part 21 IP – Patient Leakage Current 22 U – Probe Voltage 23		
 9 9.1 9.2 9.3 9.4 9.5 9.6 9.7 9.8 9.9 9.10 	Single Measurements14RPE – Protective Conductor Resistance forProtection Class I Devices15RINS – Insulation Resistance Measurement16for Protection Class I Devices16RINS – Insulation Resistance Measurement17for Protection Class II Devices17IPE – Protective Conductor Current18IT – Touch Current19IE – Device Leakage Current20IA – Leakage Current from the ApplicationPart21IP – Patient Leakage Current22U – Probe Voltage23U – Measuring Voltage24		
 9 9.1 9.2 9.3 9.4 9.5 9.6 9.7 9.8 9.9 9.10 9.11 	Single Measurements14RPE – Protective Conductor Resistance forProtection Class I Devices15RINS – Insulation Resistance Measurement16for Protection Class I Devices16RINS – Insulation Resistance Measurement17for Protection Class II Devices17IPE – Protective Conductor Current18IT – Touch Current19IE – Device Leakage Current20IA – Leakage Current from the ApplicationPart21IP – Patient Leakage Current22U – Probe Voltage23U – Measuring Voltage24tPRCD – PRCD Time to Trip		
 9 9.1 9.2 9.3 9.4 9.5 9.6 9.7 9.8 9.9 9.10 9.11 	Single Measurements14RPE – Protective Conductor Resistance forProtection Class I Devices15RINS – Insulation Resistance Measurement16for Protection Class I Devices16RINS – Insulation Resistance Measurement17for Protection Class II Devices17IPE – Protective Conductor Current18IT – Touch Current19IE – Device Leakage Current20IA – Leakage Current from the ApplicationPart21IP – Patient Leakage Current22U – Probe Voltage23U – Measuring Voltage24tPRCD – PRCD Time to Trip25		
 9 9.1 9.2 9.3 9.4 9.5 9.6 9.7 9.8 9.9 9.10 9.11 9.12 	Single Measurements14RPE – Protective Conductor Resistance forProtection Class I Devices15RINS – Insulation Resistance Measurement16for Protection Class I Devices16RINS – Insulation Resistance Measurement17for Protection Class I Devices17IPE – Protective Conductor Current18IT – Touch Current19IE – Device Leakage Current20IA – Leakage Current from the ApplicationPart21IP – Patient Leakage Current22U – Probe Voltage23U – Measuring Voltage24tPRCD – PRCD Time to Trip25P – Functions Test26		
 9 9.1 9.2 9.3 9.4 9.5 9.6 9.7 9.8 9.9 9.10 9.11 9.12 9.13 	Single Measurements14RPE – Protective Conductor Resistance forProtection Class I Devices15RINS – Insulation Resistance Measurement16for Protection Class I Devices16RINS – Insulation Resistance Measurement17for Protection Class I Devices17IPE – Protective Conductor Current18IT – Touch Current19IE – Device Leakage Current20IA – Leakage Current from the ApplicationPart21IP – Patient Leakage Current22U – Probe Voltage23U – Measuring Voltage24tPRCD – PRCD Time to Trip25P – Functions Test26EL 1 – Function Testing of Extension Cords27		
 9 9.1 9.2 9.3 9.4 9.5 9.6 9.7 9.8 9.9 9.10 9.11 9.12 9.13 9.14 	Single Measurements14RPE – Protective Conductor Resistance forProtection Class I Devices15RINS – Insulation Resistance Measurement16for Protection Class I Devices16RINS – Insulation Resistance Measurement17for Protection Class I Devices17IPE – Protective Conductor Current18IT – Touch Current19IE – Device Leakage Current20IA – Leakage Current from the ApplicationPart21IP – Patient Leakage Current22U – Probe Voltage23U – Measuring Voltage24tPRCD – PRCD Time to Trip25P – Functions Test26EL1 – Function Testing of Extension Cords27EXTRA – Special functions28		
 9 9.1 9.2 9.3 9.4 9.5 9.6 9.7 9.8 9.9 9.10 9.11 9.12 9.13 9.14 9.15 	Single Measurements14RPE – Protective Conductor Resistance forProtection Class I Devices15RINS – Insulation Resistance Measurement16for Protection Class I Devices16RINS – Insulation Resistance Measurement17for Protection Class II Devices17IPE – Protective Conductor Current18IT – Touch Current19IE – Device Leakage Current20IA – Leakage Current from the ApplicationPart21IP – Patient Leakage Current22U – Probe Voltage23U – Measuring Voltage24tPRCD – PRCD Time to Trip25P – Functions Test26EL1 – Function Testing of Extension Cords27EXTRA – Special functions282-Pole Measurements with P1 and P2 Test30		

	Page
9.16	Measurement with Current Clamp Sensor at Permanently Installed DUTs of Safety Class I
9.17	Measurements with Test Adapter
10	Test Sequences in Accordance with
	Standards
10.1	General Procedure
10.2	Evaluation Procedure
10.3	Sample Test Sequence
11	Measurement Parameters for Individual Measurements and
	Test Sequences
12	Repair and Replacement Parts Service Calibration Center and Rental Instrument
	Service
13	Product Support 38
14	IZYTRONIQ Data Processing
	Software

1 Safety Precautions

SECUTEST ST BASE(10), SECUTEST ST PRO and SECULIFE ST BASE(25) test instruments are manufactured and tested in accordance with the following safety regulations:

IEC/EN 61010-1 / VDE 0411-1, DIN VDE 0404, IEC/EN 61577 / VDE 0413-2,-4 / DIN EN 61557-16 / VDE 0413-16

The "automatic test sequences" are semiautomatically controlled sequences whose progress is interrupted by safety-relevant stoppages and the associated warnings and instructions. As a result, the level of protection provided to the user is greater than demanded by sections 4.1.6 and 4.1.7 of DIN EN 61557-16 with regard to "automatic test sequences".

The safety of the user, the test instrument and the device under test (electrical equipment or electrical medical device) is only assured when the instrument is used for its intended purpose.

Read these condensed operating instructions and the full operating instructions carefully and completely before placing your test instrument into service (available at our homepage www.gossenmetrawatt.com for download). Follow all instructions contained therein. Make sure that the operating instructions are available to all users of the instrument.

Tests may only be performed by a qualified electrician, or under the supervision and direction of a qualified electrician. The user must be instructed by a qualified electrician concerning performance and evaluation of the test.

Suitable personal safety equipment is required.

If you use any active or passive implanted medical devices, please consult your doctor or the manufacturer of these devices.

Note Note

Manufacturers and importers of electrical medical devices must provide documentation for the performance of maintenance by trained personnel.

Observe the following safety precautions:

- The instrument may only be connected to electrical systems (TN, TT or IT) with a maximum of 240 V which complies with applicable safety regulations (e.g. IEC 60346, VDE 0100) and is protected with a fuse or circuit breaker with a maximum rating of 16 A.
- Measurements within electrical systems are prohibited.
- Be prepared for the occurrence of unexpected voltages at devices under test (for example, capacitors can be dangerously charged).
- Make certain that the measurement cables are in flawless condition, e.g. no damage to insulation, no cracks in cables or plugs etc.
- When using a test probe with coil cord (SK2W): Grip the tip of the test probe firmly, for example during insertion into a jack socket. Tensioning at the coil cord may otherwise cause the test probe to snap back resulting in possible injury.
- Measurement of insulation resistance and equivalent leakage current (leakage current alternative measuring methods)

Testing is conducted with up to 500 V. Current limiting is utilized (I < 3.5 mA), but if terminals L or N at the test socket are touched, electrical shock may occur which could result in consequential accidents.

During operation with line voltage: Exposed conductive parts may conduct dangerous touch voltage during testing. Do not touch under any circumstances! Use a special cover in order to avoid touch contact.

Mains power is disconnected at the instrument if leakage current exceeds approx. 10 mA (can be switched to 30 mA). However, this does not fulfill the requirements specified for a PRCD. If the "Proceed in case of limit violation" setting is used, enhanced safeguarding against touch contact and a 30 mA RCD must be used, and personal protective equipment (PPE) must be worn (secure work-station).

Attention!

The function test may only be performed after the DUT has successfully passed the safety test!

• Probe check for probe connector P1: Please perform a probe check after each test.

Attention!

∕!∖

If there is a fuse defect in test probe P1 after having started the test, all subsequent measurements which are performed with this measurement path might be erroneously rated as good!

Fuse replacement

The fuses may only be replaced when the instrument is voltage-free, i.e. the instrument must be disconnected from mains supply power and may not be connected to a measuring circuit. The fuse type must comply with the specifications in the technical data or the labeling on the instrument.

Opening the instrument / repairs

The instrument may only be opened by authorized, trained personnel in order to ensure flawless operation and to assure that the guarantee is not rendered null and void. Even original replacement parts may only be installed by authorized, trained personnel. If it can be ascertained that the instrument has been opened by unauthorized personnel, no guarantee claims can be honored by the manufacturer with regard to personal safety, measuring accuracy, compliance with applicable safety measures or any consequential damages.

Any warranty claims will be forfeited when the warranty seal has been damaged or removed.

Switching power consumers (max. 16 A*)

Be absolutely sure to adhere to the sequence specified below when switching the live device under test. This prevents excessive wear of the mains relays at the test instrument. Before measurement:

- 1) **DUT**: Turn the DUT off via its own switch.
- 2) **Tester**: Switch line voltage to the test socket.
- 3) **DUT**: Turn the DUT on via its own switch.

After measurement:

- 4) **DUT**: Turn the DUT off via its own switch.
- Tester: Deactivate line voltage to the test socket.
- * for currents > 16 A AC please use adapter AT3-IIS32 (Z745X), for example

The test instrument may not be used:

- If external damage is apparent, for example if parts which conduct dangerous touch voltage are freely accessible, if the display is broken or defective (in which case dangerous voltage or mains connection errors might no longer be indicated)
- If the seal or sealing lacquer has been removed as the result of repairs or manipulation carried out by a non-authorized/noncertified service provider.
- With damaged connection and/or measurement cables and patient ports, e.g. interrupted insulation or kinked cable
- If the instrument no longer functions flawlessly
- After serious damage due to transport

In such cases, the instrument must be removed from operation and secured against unintentional use.

Meanings of Symbols on the Instrument

The symbols on the instrument have the following meanings:



Warning regarding dangerous electrical voltage



Warning concerning a point of danger (attention: observe documentation!)



Indicates European Conformity



This device may not be disposed of with the trash. Further information regarding the WEEE mark can be accessed on the Internet at www.gossenmetrawatt.com by entering the search term "WEEE".



If the guarantee seal is damaged or removed, all guarantee claims are rendered null and void.

QR CODE QR CODE is a registered trademark of DENSO WAVE INCORPORATED

2 Scope of Delivery

The scope of delivery varies depending on which instrument variant has been ordered, and is country-specific. Information concerning the scope of delivery can be found in your order and the data sheet, in which all order information is listed.

Example of a standard variant (standard model):

- 1 SECUTEST ST BASE, SECUTEST ST PRO or SECULIFE ST BASE(25) test instrument
- 1 Mains power cable
- 1 Test probe, 2 m, not coiled
- 1 USB cable, USB A to USB B, length: 1.0 m
- 1 Plug-on alligator clip
- KS17-ONE cable set for voltage measuring inputs (only with SECUTEST PRO or an instrument with feature I01 and SECULIFE ST BASE(25))
- 1 Calibration certificate
- 1 Condensed operating instructions
- Set of complete operating instructions available on the Internet for download from

www.gossenmetrawatt.com

1 Card with registration key for IZYTRONIQ BUSINESS Starter software

3 Initial Start-Up

3.1 Mains Connection

Nominal mains values: 100 to 240 V, 50 Hz to 400 Hz

Connect the test instrument to the mains cable via its inlet plug and insert the mains plug into an electrical outlet. The function selector switch can be set to any position. If a mains outlet (earthing contact outlet) is not available, or if only a 3-phase outlet is available, the adapter socket can be used to connect the phase conductor, the neutral conductor and the protective conductor. The adapter socket has three permanently attached cables and is included with the KS13 cable set (see wiring diagram in the operating instructions).

Attention!

∕ı∖

If connection is not possible via an earthing contact outlet: Shut down mains power first. Then connect the cables from the coupling socket to the mains using pick-off clips in accordance with the diagram. Disconnection from mains power is only possible with the mains plug.

Measurements in IT Systems

The setting **IT system** can be activated in selector switch position **SETUP** (Setup 1/3) under sub-menu **All Measurement**: Parameter **"Meas. at IT-mains" = Yes:** active leakage current measurements (and/or all measurements which include the PE at the mains connection end) are blocked. Test sequences which contain such kind of measurements are disabled as well.

3.2 Detection of Mains Connection Errors

The device automatically recognizes mains connection errors if the conditions in the following table have been fulfilled. The user is informed of the type of error, and all measuring functions are disabled in the event of danger.

Type of Connection Error	Message	Condition	Measure- ments
Voltage at protec- tive conductor PE to finger contact (START/STOP key)	Display at the instrument	Press START/ STOP button U > 25 V Button \rightarrow PE: $< 1 M\Omega^2$	All measure- ments disabled
Protective conduc- tor PE & phase conductor L reversed and/or neutral conductor N interrupted		Voltage at PE > 100 V	Impossible (no supply power)
Line voltage < 180 V / < 90 V (depending on mains)		$\begin{array}{c} {\sf U}_{\rm L-N}{<}180{\rm V}\\ {\sf U}_{\rm L-N}{<}90{\rm V} \end{array}$	Possible under certain circum- stances ¹
Test on IT/TN system	Display at the instrument	Connection N \rightarrow PE > 20 k Ω	Possible under certain circumstances

¹ 10 A/25 A R_{PE} measurements are only possible with line voltages of 115/230 V and line frequencies of 50/60 Hz.

if the test person is highly insulated, the following error message may appear: "Interference voltage at PE of mains connection"

Attention!

In the event of mains connection errors as described in either of the first two cases in the table above, immediately disconnect the test instrument from the mains and arrange to have the error eliminated!

Note 🔊

Voltage at the electrical system's protective conductor PE may result in distorted measurement values during testing for the absence of voltage, or during leakage voltage measurements.

4 **Overview of Functions of the Testers**

Switch	Measuring functions,			
setting,	test current/voltage			
descrip-				
tion as of				
Single m	easureme	nts, rotary switch level: green		
Measure	ments at	voltage-free objects		
R _{PE}	R _{PE}	protect. conductor resistance		
Page 15	lp	test current (200 mA) SECUTEST ST BASE(10)/PRO SECULIFE ST BASE: 10 A ¹ (Feature G01) SECULIFE ST BASE25: 25 A ¹) (Feature G02)		
R _{INS}	R _{INS}	insulation resistance		
Page 16	U _{INS}	test voltage		
Measure	ments at	DUTs with line voltage		
IPF	I _{PE}	prot. conductor current, TRMS		
	I _{PE~}	AC component		
	I _{PE=}	DC component		
	UIPF	test voltage		
Page 18	U _{Gen}	reference voltage (alternative)		
ŀт	$I_{T\simeq}$	touch voltage, TRMS		
	I _{T~)}	AC component		
	$I_{T=}$	DC component		
	U _{LPE}	test voltage		
Page 19	U _{Gen}	reference voltage (alternative)		
I _E	$I_{E\simeq}$	device leakage current, TRMS		
	I _{E~}	AC component		
	$I_{E=}$	DC component		
	U _{LPE}	test voltage		
Page 20	U _{Gen}	reference voltage (alternative)		
I _A	I _A ∼	leakage current from app. part		
	U _{LPE}	test voltage		
Page 21	U _{Gen}	reterence voltage (alternative)		
Ip	I _{P∼}	patient leakage current, TRMS		
	I _{P∼}	AC component		
Dade 22	I _{P=}	DC component		
1 aye 22	ULPE	test voltage		
U	U <u>~</u>	probe voltage, IRMS		
	U~	ait. voltage component		
	U	urrect voltage component		
	U <u>~</u>			
Page 23	U~	AU VOILage component -		
1 2	U	DU VOILage Component -		
	ι _a	line to trip for TU/30 mA PRCD		
Page 25	ULN	line vollage at the test socket		

Switch	Measuring functions,			
setting,	test current/voltage			
descrip-				
tion as of				
P	Function test at the test socket			
	I current between L and N			
	U voltage between L and N			
	f frequency			
	P active power			
	S apparent power			
Page 26	PF power factor			
Probe m	easuring functions			
EL1	Extension cord function test with EL1/VL2E/			
D 07	AI3-IIIE adapter: continuity, short-circuit, re-			
Page 27	Person wites			
EXIKA	software updates			
	°C Temperature measurement ² with Pt100/Pt1000			
Page 28	IZ Measurement of current at clamp with cur- rent clamp sensor			
Test sequ	ences per standard rotary switch level: orange			
Page 32				
Preconfig	gured (freely selectable) test sequences			
A1	VDE 0701-0702, passive measurement type, test socket			
A2	VDE 0701-0702, active measurement type, test socket			
A3	VDE 0701-0702, parameters configuration for EDP (active)			
A4	IEC 62353 (VDE 0751), passive measurement type			
A5	IEC 62353 (VDE 0751), active measurement type			
A6	IEC 60974-4, connection type: test socket			
A7	IEC 60974-4, connection type: AT16-DI/AT32-DI			
A8	VDE 0701-0702, measurement type extension cord test (RPE, RISO), EL1/VL2E/AT3-IIIE adapter			
A9	VDE 0701-0702 , connection type, measurement type, protection category – in each case automatic			

¹ 10 A/25 A-R_{PE} measurements are only possible with line voltages of 115 V/230 V and line frequencies of 50 Hz/60 Hz.

 ³ Measurement of time to trip not possible in IT systems.
 ⁴ No checking for reversed polarity takes place when the EL1 adapter is used.

² Voltage measuring inputs only for **SECUTEST ST PRO** (or for devices with feature I01) and SECULIFE ST BASE(25)

Note Note

Changes in test sequences A1 ... A9 are preserved even after switching off the test instrument.

Note Note

Features involving expansions (firmware) which can be enabled are available for an additional charge if they're not included in the scope of delivery. Example: Feature KD01, "Z853S – SECUTEST DB COMFORT", as mentioned in this document. Refer to the test instrument's operating instructions for further information.

5 User Interface Symbols – Parameter and Softkey Symbols

Sym-	Setup	Parameters and their significance
bols	Page	Complete overviews of all symbols are included in the full operating instructions.
ĽÅ	1/3	All measurements: Het voltage L-PE: voltage to which the measured values for leakage current have been standardized; Gnd fault sens.: continuous residual current monitoring (10/30 mA)
		Automatic measurements: set parameters for test sequences: start and end view, inclusive operation uncertainty (yes/no), auto measurement point (yes/no)
	1/3	Database: Image: Contract of the second
\mathbf{X}	1/3	System: set general device parameters; 12 ⁰ date/time, ↓) volume, ★ brightness, ♣ default settings, CHECK self-test
믭	2/3	Printer: printer selection for USB master interface
	2/3	Tester: 🗐 select tester from list, 🖈 add new tester
3	2/3	Culture : select language for operating instructions, keyboard and measuring sequences by acknowledging the respective national flag; Reboot necessary!
₽	2/3	Optionally connected external devices ✓ USB stick, keyboard / barcode scanner, ⊟ printer
x	3/3	System information: query software and hardware version, serial number, build number, calibration data and storage occupancy
	—	Functions and their significance
		Set classification parameters for the respective test sequence
		(test sequences switch settings A1 A9)
1		Accept parameters, acknowledge message
X		Abort single measurement or test sequence
X		Evaluate measurement of visual inspection with 0K or not 0K (toggle key)
		Continue test, next test step in the test sequence
	⊳-⊦-⊦- ⊳	Symbol left: Direct selection key measurement type (connection type) or measur- ing method (direct) / Symbol right: Selection between two states (no submenu)
		Start evaluation – record measured value. Each time this softkey is pressed, an additional measured value is saved and the number is increased by one.
S	3	Symbol left: Repeat measured value recording Symbol right: Repeat test step in the test sequence
ात्ती	ਛੋ	Symbol left: Delete measured value
	(**)	Symbol right: Skip individual tests in the test sequence
		Display measured values from performed measurements and test sequences
		Magnifying glass symbol: show (+) or hide (-) details regarding database objects or selected measurements
		Enter a new ID for a test object either before or after a test, and in case the ID has not yet been entered to the structure
		Save measurement data / save measurement data as (with display of directory path / ID or new entry of an ID other than the preselected one)

6 Internal Database

6.1 Creation of Test Structures

A complete test structure with data regarding customers and devices under test be created in the test instrument. This structure makes it possible to store the results of single measurements or test sequences of test objects belonging to various customers. Manual single measurements can be grouped together into a so-called "manual sequence".

Up to 50,000 data records can be stored in the test instrument. The following applies in this regard: 1 data record = 1 DUT or location node or customer or individual measurement.

A complete description of database creation is included in the full operating instructions for your test instrument.

6.2 Export – Transmission and Storage of Test Structures and Measurement Data

Structures set up in, and measurement data saved to the test instrument can be imported to the **IZYTRONIQ** report generating software via a plugged-in USB stick (PRO and/or Feature KB01 only) or via the USB slave port. Data can then be saved to the PC and reports can be generated.

😰 Note

Data transfer to **IZYTRONIQ** should not be started during single measurements or test sequences.

Furthermore, you can save the database to a plugged-in USB stick for subsequent restoring to the device memory.

6.3 Import (PRO and/or Feature KB01 only)

The test structures created at the PC with the help of the report generating software can be loaded into the test instrument via an USB stick or via the USB slave port.

7 Data Input

7.1 Keyboard or Softkey Entries

After selecting **ID** or any other object parameter, a keyboard is displayed which allows for the entry of alphanumeric characters via the fixed function keys and the softkeys. Alternatively, entries can also be made with the help of a USB keyboard or barcode scanner which is connected to the instrument.

Procedure

(example: entering a DUT designation)

- 1 Switch the keyboard to uppercase, lowercase or special characters with the abc key (Abc, ABC, Symb).
- 2 Select the desired alphanumeric character or a line break with the scroll keys (left, right, up and down). The selection cursor can be accelerated by pressing and holding the respective scroll key.
- 3 After pressing the A key, the respective character appears in the display field.
- 4 Repeat steps 1 through 3 until the complete designation is shown in the display field.
- 5 After pressing the green checkmark, the selected character string is saved.

g 🗸

7.2 Entry via Touch Screen (SECUTEST ST PRO and/or Feature E01 only)

The touch-screen allows for the convenient entry of data and comments, parameters and direct parameter selection.



8 Notes on Saving Single Measurements and Test Sequences

At the end of each test, test results can be saved under an ID number which is unequivocally assigned to the respective test object. Depending on the initial situation, i.e. whether or not a test structure or database is already available or an ID has already been entered, the following different procedures are used for saving:

Variant 1 – pre-selection of an existing ID You've already set up a test structure in the test instrument or loaded one from the IZYTRONIQ.

Open the database view before starting the measurement by pressing the **MEM** key. Then select the test object or its ID within the test structure by pressing the respective scroll key. Exit the database view (MEM navigation) by pressing **ESC** and start the measurement. Press the **Save as** , key at the end of the measurement. The display is switched to the **SAVE** view. The ID appears with a green or orange background. Press the **Save** , key in order to complete the procedure.

Variant 2 – entry of an existing ID at the end of the test

You've already set up a test structure in the test instrument or loaded one from the **IZYTRONIQ** (SECUTEST PRO only). You perform the measurement without first opening the database. No test object was previously selected in the database. Press the **Save as** , key at the end of the measurement. The following message appears: "No DUT selected!" Press the **ID** key. The softkey keyboard appears.

If you enter an ID here which is already in the database, the database view appears automatically (MEM navigation) and the test object's ID is displayed inversely. Acknowledge the entry by pressing the ✓ key. The display is switched to the SAVE view. The ID appears with a green or orange background. Press the **Save** 🕞 key once again in order to complete the procedure.

Variant 3 – entry of a new ID at the end of the test

You haven't yet set up a test structure in the test instrument, or the ID is not included in the existing structure.

Press the **Save as** , key at the end of the measurement. The following message appears: "No DUT selected!" Press the **ID** key in order to enter the test object's ID. The softkey keyboard appears.

If you enter an ID here which is **not yet** included in the database, a prompt appears asking you if you want to enter a new object.

- If you press I, the database view appears (MEM navigation). Go to the next page (Process objects 2/3) by pressing **b**. and then enter a new test object. Press to this end. All possible object types are displayed. Press "DUT". The newly entered ID appears in red to the right of the ID parameter. Acknowledge the entry by pressing the 🗸 key. The display is switched to the database view (MEM navigation). The newly entered test object is displayed inversely in the structure. Press **ESC** in order to return to the SAVE view. The ID appears with a green or orange background. Press the 📙 key once again in order to complete the procedure.
- ESC: If you don't want to save any measured values, press ESC twice in order to go to the measuring view. If you press ESC again, a prompt appears asking whether or not you want to delete the measuring points in order to continue with the measurement without saving.

9 Single Measurements

Any measuring duration is possible. The respective measurement is ended by pressing **START/STOP**. No limit values have been entered for single measurements. As a result, no evaluation of the measurement results takes place.

Procedure for measuring with save function and pre-selection of the (ME) device

If you'd like to save your single measurements to selected (ME) devices in a database (see section 6), the following procedure is advisable.

- 1 Activate the database view (MEM navigation) by pressing the **MEM** key.
- Select the (ME) device or its ID number for the following measurements with the scroll keys.
- 3 Return to the measuring view by pressing the ESC key or the START/ STOP key.
- 4 Start the test with the **START/STOP** key before switching the DUT on. The measured value recording symbol shown at the right appears. Each time this key is pressed, the currently displayed value is saved to the clipboard and the number shown in the symbol is increased by one.
- 5 Switch off the DUT before finishing the test with the **START/STOP** key.

The **Save as** symbol appears (floppy disk icon with the number of measured values saved to the clipboard).

- 6 If you press the save symbol now, the display is switched to the SAVE view, where the pre-selected (ME) device is highlighted.
- 7 After pressing the **Save** symbol once again, acknowledgement of successful storage appears. At the same time, the display returns to the measuring view.

Procedure for measuring with save function and subsequent entry of the (ME) device

As an alternative to the procedure described above, you can start with step 4 and, after measurement has been completed, assign the results to a (ME) device or its ID number which is included in the database: manually by selecting **ID** and entering the ID via the alphanumeric keyboard, or by scanning a barcode.

Select DUT



Start \rightarrow stop \rightarrow initiate saving

$\mathsf{Check} \to \mathsf{end} \ \mathsf{saving}$



9.1 RPE – Protective Conductor Resistance for Protection Class I Devices



Set parameters		
Meas. Parameter	Meaning	
Mode (Measurement type) 01+++0 admissible test current IP		
passive: PE(TS) – P1 @ IP = 200 mA/10 A	Testing between the 2 protective conductor terminals: at test sock- et ⁴ and test probe P1	
active: PE(PD) – P1 @ IP = 200 mA/25 A	Like PE(TS) – P1 but with mains voltage to socket and with continu- ously increasing DC current (PRCDs)	
PE(mains) – P1 Permanently connected devices @ IP = 200 mA/10 A	Testing between ground terminal at mains and test probe P1	
PE(Mains) – P1 clip	@ IP = 10 A, see section 9.16	
P1 – P2 @ IP = 200 mA/10 A/25 A	Only test devices with feature H01: 2-pole measurement between test probe 1 and 2, see section 9.15	
IP(set) Ip		
200 mA	Test cur.: 200 mA AC (+/-/± DC)	
10 A ¹	Test current: 10 A (Feature G01)	
25 A ²	Test current: 10 A (Feature G02)	
f – only at 200 mA ~ (AC)		
50 to 200 Hz	Test sequence (adjustable in increments)	
Offset		
> 0 to < 2 Ω^3	Zero balancing for selected ref. point.	

- SECUTEST ST BASE(10) / SECUTEST ST PRO / SECULIFE ST BASE
- ²⁾ SECULIFE ST BASE25
- The selected offset value is permanently stored to memory and adapted for measurements in selector switch position A1 ... A9.
 Connection also via EL1, VL2E, AT3 adapter, AT16DI/AT32DI





- Connect the DUT to the test socket.
- Contact all conductive parts which are connected to the protective conductor with test probe P1.

Special case: permanently installed DUT



9.2 RINS – Insulation Resistance Measurement for Protection Class I Devices



Connection also via EL1, VL2E, AT3-IIIE, AT3-IIS, AT3-II S32, AT16DI/AT32DI or CEE adapter

LN(TS) - PE(TS)

LN(TS) - PE(TS)

9.3 RINS – Insulation Resistance Measurement for Protection Class II Devices



9.4 **IPE – Protective Conductor Current** A **Select Measuring Function**





3/

3 Set parameters			
Meas. Parameter	Meaning		
Mode (Measurement type)			
Direct	Direct measuring method (via test socket, AT16DI/AT32DI)		
Differential	Differential current measurement (via test socket)		
Alternative	Equivalent leakage current mea- suring method (via test socket ¹)		
AT3 Adapter	Only test devices with feature IO1: Measurement with adapter AT3- IIIE, AT3-IIS or AT3-II S32 See section 9.17		
Clip	Only test devices with feature IO1: See section 9.16		
Single Fault (SFC) – fo	r direct measurement type only		
Normal condition	No single fault simulation active		
N interrupted	Fault simulation - only phase and protective conductor are con- nected with the DUT ²)		
Polarity – for direct, differential measurement and AT3 adapter only			
∼ः normal ∼∵ reverse	Selection of polarity for line volt- age at test socket		
Connection also via VI 2E AT2 adaptor AT16DI/AT22DI			

Connection also via VL2E, AT3 adapter, AT16DI/AT32DI

2) only suitable for connection of DUT with test socket. Not suitable for measurements at AT16DI or AT32DI adapter.

Prior to all leakage current measurements, please make sure that the measurement parameters ...Ref. voltage L-PE" and "Testingfreq. Alt" have been correctly set in the SETUP, see section 11.





- Connection also via AT3-IIIE, AT3-IIS, AT3-II S32, AT16DI/AT32DI
- ² only suitable for connection of DUT with test socket. Not suitable for measurements at AT16DI or AT32DI adapter.

Prior to all leakage current measurements, please make sure that the measurement parameters "Ref. voltage L-PE" and "Testingfreq. Alt" have been correctly set in the SETUP, see section 11.



9.6 IE – Device Leakage Current

1 Select measuring function



A Set narameters



3/

Meas. Parameter	Meaning		
Mode (Measurement type)			
Direct	Direct measuring method (via test socket ¹), optional probe contact		
Differential	Differential current measurement (via test socket)		
Alternative	Equivalent leakage current mea- suring method with probe contact (via test socket, AT16DI/AT32DI)		
AT3 adapter	Only test devices with feature IO1: Measurement with adapter AT3- IIIE, AT3-IIS or AT3-II S32 See section 9.17		
Clamp	Only test devices with feature IO1: see section 9.16		
Polarity ²⁾ – for direct, differential measure- ment and AT3 adapter only			
∼≕ normal ∼≈ reverse	Selection of polarity for line volt- age at test socket		
1			

Connection also via AT16DI/AT32DI (only differential current methtod useful)

2) Measurement must be performed for both mains polarities and the largest value is documented Prior to all leakage current measurements, please make sure that the measurement parameters "Ref. voltage L-PE" and "Testingfreq. Alt" have been correctly set in the SETUP, see section 11.

Connect DUT
Direct / Alt
Connect the DLIT to the test seeket

- Connect the DUT to the test socket.
 Contact accessible, conductive parts
- Contact accessible, conductive parts which are not connected to the protective conductor with test probe P1.
- For DUTs with application parts: additionally contact the short-circuited inputs for the application parts with test probe P1.



9.7 IA – Leakage Current from the Application Part



Prior to all leakage current measurements, please make sure that the measurement parameters "Ref. voltage L-PE" and "Testingfreq. Alt" have been correctly set in the SETUP, see section 11.



9.8 IP – Patient Leakage Current

Permanent connection part Sigue on application part Sigue on application part Sigue on application part Foldarity - for direct, differential measure- Sigue Save measurements under ID no.	Select measur	ing function	make sure that the measurement parameters "Ref. voltage L-PE" and "Testingfreq. Alt." have been cor- rectly set in the SETUP, see section 11.
 Select parameters Image: Select parameters Image: Select paramete	IP CON		Connect DUT
 3 Set parameters Meas. Parameter Meaning Mode (Measurement type) Direct P1 Direct measuring method (via test socket) with test probe P1 Permanent connection Permanently connected DUT P1 Single Fault (SFC) – for measrement type direct P1 only Normal condition no single fault simulation active - for measrement type direct P1 only Normal condition no single fault simulation active - only phase and protective conductor are connected with the DUT 1) PE interrupted Fault simulation active - protective conductor is disconnected from the DUT of the duration of measurement Nom. voltage on Fault simulation active - low voltage on application part Polarity – for direct, differential measure- 	2 Select parame	A A A A ULPE V SFC Normal cond.	 Connect the DUT to the test socket. Contact the short-circuited inputs for the application parts with test probe P1.
Meas. Parameter Meaning Mode (Measurement type) Image: Construct of the service of the serv	3 Set parameter	s 🔀	5 Start test
Mode (Measurement type) Image: Construction of the duration of measurement type) Image: Construction of the duration of measurement type) Direct P1 Direct measuring method (via test socket) with test probe P1 Image: Construction of the duration of measurement type direct P1 only Permanent connection Permanently connected DUT P1 Direct Measurement type direct P1 only Image: Construction of the duration active only phase and protective conductor are connected with the DUT 1) Image: Construction of measurement Nom. voltage on application part Fault simulation active - low voltage on application part Fault simulation active - low voltage on application part Polarity – for direct, differential measure- Image: Construction of measurements under ID no.	Meas. Parameter	Meaning	
Direct P1 Direct measuring method (via test socket) with test probe P1 Permanent connection Permanently connected DUT Direct Main Permanently connected DUT Single Fault (SFC) - for measrement type direct P1 only Direct Main Permanently connected DUT Normal condition no single fault simulation active N interrupted Fault simulation active - only phase and protective conductor are connected with the DUT 1) PE interrupted Fault simulation active - protective conductor is disconnected from the DUT for the duration of measurement Nom. voltage on application part Fault simulation active - low voltage on application part Polarity – for direct, differential measure- Save measurements under ID no.	Mode (Measuremen	it type) C-+++D	STOP
Permanent connection Permanently connected DUT P1 Direct Direct Single Fault (SFC) – for measrement type direct Pi Normal condition no single fault simulation active Normal condition no single fault simulation active - only phase and protective conductor are connected with the DUT ¹ PE interrupted Fault simulation active - protective conductor is disconnected from the DUT for the duration of mea- surement Image: Stop test Nom. voltage on application part Fault simulation active - low vol- tage on application part Image: Stop test Polarity – for direct, differential measure- Image: Stop test	Direct P1	Direct measuring method (via test socket) with test probe P1	6 Acknowledge line voltage warning
Single Fault (SFC) – for measmement type direct P1 only Normal condition no single fault simulation active N interrupted Fault simulation active - only phase and protective conductor are connected with the DUT 1) PE interrupted Fault simulation active - protective conductor is disconnected from the DUT for the duration of mea- surement Nom. voltage on application part Fault simulation active - low vol- tage on application part Polarity – for direct, differential measure- Save measurements under ID no.	Permanent connection P1	Permanently connected DUT	Direct
Normal condition no single fault simulation active N interrupted Fault simulation active - only phase and protective conductor are connected with the DUT 1) PE interrupted Fault simulation active - protective conductor is disconnected from the DUT for the duration of measurement Nom. voltage on application part Fault simulation active - low voltage on application part Polarity – for direct, differential measure- Image: Step test	Single Fault (SFC) – P1 only	for measrement type direct	
N interrupted Fault simulation active - only phase and protective conductor are connected with the DUT 1 are connected with the DUT 1 PE interrupted Fault simulation active - protective conductor is disconnected from the DUT for the duration of measurement Nom. voltage on application part Fault simulation active - low voltage on application part Polarity – for direct, differential measure- Image: Conduct Direct and Dire	Normal condition	no single fault simulation active	Save measured values to clipboard
PE interrupted Fault simulation active - protective conductor is disconnected from the DUT for the duration of measurement Nom. voltage on application part Fault simulation active - low voltage on application part Polarity – for direct, differential measure- Image: Conductor is disconnected from the DUT for the duration of measure- 9 Save measurements under ID no.	N interrupted	Fault simulation active - only phase and protective conductor are connected with the DUT ¹⁾	Ston test
Nom. voltage on application part Fault simulation active - low vol- tage on application part Polarity – for direct, differential measure- Polarity – for direct,	PE interrupted	Fault simulation active - protective conductor is disconnected from the DUT for the duration of mea- surement	START
Polarity – for direct, differential measure- 🚗 🥹 Save measurements under ID no.	Nom. voltage on application part	Fault simulation active - low vol- tage on application part	
ment and AT3 adapter only 🛛 🔁	Polarity – for direct ment ar	t, differential measure- 🛛 🚝 d AT3 adapter only	Save measurements under ID no.
reverse Selection of polarity for line voltage at test socket	reverse	Selection of polarity for line voltage at test socket	

Prior to all leakage current measurements, please



9.10 U – Measuring Voltage

Select measuring function

Ð

SECUTEST ST PRO and SECULIFE ST BASE only and/or Feature I01:









Attention!

Only use the enclosed contact-protected KS17-ONE measurement cables for the measurement of dangerous voltages, please.

Special case: permanently installed DUT



- \Box For testing mains power packs and charging units: Connect the DUT mains terminal with the test socket
- Connect the DUT output, e.g. for measuring safety extra low voltage (SELV), with sockets V and COM.



9.11 tPRCD – PRCD Time to Trip (portable residual current device)



power factor and current consumption can only be measured, however, if the DUT is directly connected with the test socket or via the CEE adapter (single-

phase CEE socket only).

9.12 P – Functions Test



9.13 EL1 – Function Testing of Extension Cords



For the testing of R_{PE} and $\mathsf{R}_{\mathsf{INS}}$ see respective single measurements.



See section 10, "Test Sequences in Accordance with Standards" (switch setting A8) with regard to testing extension cords per DIN VDE 0701-0702, for which $R_{\rm PE}$ and $R_{\rm INS}$ are measured.





Connection of EL1 Adapter

- Connect the EL1 adapter to the P1 probe sockets at the test instrument.
- Connect the plug at the end of the extension cord to the test socket.
- Connect the coupling socket at the end of the extension cord to the plug at the EL1 adapter.

Connection of Test Adapters VL2E and AT3-IIIE

Connection examples are shown in section 9.17.



9 Save measurements under ID no.

9.14 EXTRA – Special functions

SECUTEST ST BASE(10)

1 Select measuring function



SECUTEST ST PRO (Feature I01) & SECULIFE ST BASE(25)

Select measuring function

EXTRA



In this case, additional measurement functions are assigned to rotary switch position EXTRA.



If a QR code is provided:

By scanning the code you can download the current operating instructions from our homepage www.gossenmetrawatt.com and read them with a tablet PC.

2 Tem	p. oder IZ
EXTRA	Measurements
	temperature
	Current (via clamp)

Select the desired measuring function.



Temp. - Temperature measurement

IZ – Current clamp measurement

9.15 2-Pole Measurements with P1 and P2 Test Probes

SECUTEST ST PRO and SECULIFE ST BASE(25) only and/or Feature H01

In case your DUT is not equipped with a country-specific mains plug that fits into the SECUTEST test socket or if it is a permanently installed DUT, the 2nd test probe, in combination with the 1st test probe, allows for 2-pole measurement (dual-lead measurement) of RPE, RINS and equivalent leakage current.

Measurements with test probe 1 against test probe 2 (P1 - P2) are electrically isolated from the mains. There is no voltage present at the test probe.

Connection Example of RPE Measurement

Measuring of protective conductor resistance RPE at permanently installed safety class I devices



Connection Example of RINS or IT Measurements

Measuring of insulation resistance RINS or touch current IT for safety class I devices



9.16 Measurement with Current Clamp Sensor at Permanently Installed DUTs of Safety Class I

SECUTEST ST PRO and SECULIFE ST BASE(25) only

SECUTEST ST PRO	Clamp		SECUTEST ST PRO
Parameter Transf. Ratio	Transformer Ratio (Switch*)	Measuring Range	Display Range with Clamp
1 mV ·1 mA	WZ		
1 1117 .1 11174	1 mV : 1 mA	1 mA 15 A	0 mA 300 A

* for WZ12C only

Connection Example for RPE Measurement (WZ12C only)



Measurement of test current by enclosing PE in the electric circuit. This type of measurement can only be selected if the test current has been set at 10 A AC.

Connection Example for IPE Measurement (Direct)



Measurement of protective conductor current by enclosing **PE** in the feeder.

Connection Example of IE Measurement (Difference Measurement)



Measurement of device leakage current by enclosing conductors **L** and **N** in the feeder.

onn mododrom	01110				
Test with Adapter	EL1	VL2E	AT3-	AT16DI	CEE-
			IIIE-	AI32DI	Adapter
DUT terminals					
Inlet plug 1P+N+PE 16 A	-	~	~	—	—
Schuko 1P+N+PE 16 A	—	~	—	-	—
CEE 1P+N+PE 16 A	—	~	~	—	~
CEE 3P+N+PE 16 A	—	~	~	v /-	~
CEE 3P+N+PE 32 A	—	~	~	_/ /	~
5 x 4 mm sockets	—	—	—	—	~
Test instrument termi	nals				
Schuko 1P+N+PE 16 A	_	_	~	~	—
Socket for test probe	—	~	~	—	—
Plug for V–COM 1	—	—	V	—	—
Active Testing					
Protective conductor cu	urrent I	PE			
 Direct method 	_		~	~	_
- Differential current	_	_	v ¹	~	_
Device leakage current	IE				
 Direct method 	—	_	~	~	_
- Differential current	—		v ¹	~	_
Touch current IT	—	—	~	~	—
Passive Testing					
Protective conductor resistance RPE	r	r	r	~	~
Insulation resistance RINS	V	~	~	~	V
Protective conductor current IPE (equiv. leak- age current method)	_	v	~	r	~
Extension cables: the f apart from RPE & RISO a	ollowin are con	g additi ducted	onal me in switc	easureme h positio	ents n EL1
single phase (3-pole)	~	~	~	—	—
3-phase (5-pole)	—	~	~	-	—
wire short circuit	~	~	~	_	_
wire interruption	~	~	~	_	_
wire reversal	_	~	~	_	_

9.17 Measurements with Test Adapter

Differential current method with SECUTEST ST PRO only

² for IPE and IG: AT3-IIS or, alternatively, AT3-II S32

A

Attention!

For information on the correct connection of test adapter and DUT as well as particular aspects during the test sequence please refer to the operating instructions of the test adapters.

Connection Example with EL1



Connection Example with VL2E



Connection Example for Protective Conductor Current Measurement IPE¹ (Direct Method) with AT3-IIIE



Connection Example for Device Leakage Current Measurement IG¹ (Differential Current Method) with AT3-IIIE



with SECUTEST ST PRO and/or Feature IO1 or SECULIFE ST BASE(25) only

10 **Test Sequences in Accordance** with Standards

If the same sequence of single tests will be run frequently (one after the other with subsequent report generation), for example as specified in the standards, it's advisable to make use of test sequences. Limit values have been entered for test sequences in accordance with standards. And thus a go/ no-go evaluation takes place during measurement based on worst-case assessment. If the momentary measured value is displayed in green, it lies within the limit values specified in the standard. If the measured value is red, is does not fulfill the requirements set forth in the standard. If the measured value is shown in **amber**, further entries are required. Even if the DUT fails just a single test step, the test sequence is aborted and testing in accordance with the selected standard is failed.

Note i de la compañía de la compañía

With the help of the SECUTEST DB **COMFORT** feature (feature KD01 or expansion Z853S), test sequences can be modified such that they're not interrupted in the event of a limit value violation. Amongst other things, this is helpful for troubleshooting during repair. Please refer to the operating instructions for further information.

10.1 General Procedure

- 1 Select the desired test sequence with the rotary switch (A1 ... A9).
- 2 If no test object has been selected, enter the ID number of the test object, for example by means of a barcode scanner, after selecting ID.
- 3 As an alternative to step 2, activate MEM the database view with the MEM key:
- 4 Select the test object with the scroll keys.
 - ESC
- 5 Return to the measuring view by pressing the ESC key.



- 7 The measured value recording symbol shown at the right appears. Each time this key is pressed, the measuring or evaluation procedure is restarted (see case B in section 10.2).
- 8 Proceed to the next measurement by pressing the key shown to the right.
- 9 At the end of the test sequence, you can generate a list of the results of the individual test steps.



- 10 If you want to view details such as the settings for the individual test steps, select the desired measurement with the cursor and press the + magnifying glass key.
- 11 The display is returned to the list of test steps by pressing the - magnifying glass kev.
- 12 Save the results of a successful test sequence by pressing the Save key.

10.2 **Evaluation Procedure**

The evaluation procedure can be started manually for some test steps within a given test sequence, but all others are run automatically.

- Case A automatic triggering of evaluation: Evaluation (with a duration of, for example, 5 seconds) is started automatically as soon as the measured value has stabilized. The worst value which occurs during this duration is saved, and automatic switching to the next test step ensues.
- Case B manual triggering of evaluation: Evaluation is started after pressing the measurement value recording symbol (display: 0). After a specified period of time has elapsed, the worst value is saved to the right of wc: (worst case and the number 1 is displayed in the measurement value recording symbol indicating that the first measured value has been saved. Pressing the measured value recording icon again restarts the evaluation procedure. If the worst value is worse that the value obtained for the

Э)	,		

previous measurement, the new value is used. However, if this value is better than the previous worst value, the original value remains in the display. Depending on whether you want to delete the last value saved to the clipboard or all values, press the symbol shown below an appropriate number of times.

Proceed to the next test by pressing the symbol shown to the right.

10.3 Sample Test Sequence





As-delivered Condition:

A1	VDE 0701-0702, passive meas. type, test socket
A2	VDE 0701-0702, active meas. type, test socket
A3	VDE 0701-0702, param. config. for EDP (active)
A4	IEC 62353 (VDE 0751), passive measement type
A5	IEC 62353 (VDE 0751), active measurement type
A6	IEC 60974-4, connection type: test socket
A7	IEC 60974-4, connec. type: AT16-DI/AT32-DI adapter
A8	VDE 0701-0702, MT ExtCord, EL1/VL2E/AT3-IIIE adapter
A9	VDE 0701-0702 , connection type, measurement type, protection category – in each case automatic

Open database

3

MEM

Select Device





5 Sequence parameters

Individual test steps can be configured with the sequence parameters, see detailed operating instructions.

6 Set classification parameters

A1 ... A9 switch setting

Meas. Parameter	Meaning
Standard	Test standard / extension cord
Protection class * ⓐ	PC1/PC2/PC3
Connection type * (b)	Test socket / permanent / adapter
Measurement type (MT) * ©	Active or passive DUIT (on test: on = passive, off = active)
Detected classifica- tion	No auto-detection: all classifica- tion parameters such as connec- tion, protection class and mea- surement type must be entered manually. Always accept: all classification parameters activated under "Auto- detection of" are detected auto- matically and accepted.
Auto-detection of	Any desired combinations for au- tomatic detection of: – Connection (b) – Protection class (SK) (a) – Measurement type (MA) (c)

* If the configurations of the classification parameters are recognized automatically, they are marked with an amber frame (in this case (a) and (b)). They must be entered manually if they're not automatically detected, or if they're detected incorrectly.

7 Connect DUT

- Connect the DUT to the test instrument in accordance with the selected test sequence.
 - Test socket
 - Permanent connection
 - Adapter

Switch position: A1 ... A7, A9

Connection depends on the type of DUT.

Switch position A8

For testing extension cords in accordance with standards: connection to the test socket via the following adapter:

- EL1: for single-phase extension cords
- VL2E/AT3-IIIE: for single- or three-phase extension cords

8 Check connection &start test sequence

The following checks are run automatically before the test sequence is started:



- Probe test P1 (whether or not the probe is connected and if fuse P1 is OK)
- Insulation test (whether or not the DUT is set up in a well-insulated fashion)
- On test and short-circuit test. In order to be able to detect a short-circuit at the DUT, testing is conducted between L and N, as well as LN and PE.

If you've set the "Detected classification" parameter for the respective test sequence to "Always accept" and the "Auto-detection of" parameter to "Connection and SK" (before triggering Start), the following additional checks will be run before the test sequence is started:

- Protection class detection for DUTs with protective conductor
- Connection check: whether or not the DUT is connected to the test socket. In the case of protection class I: whether or not the two protective conductor terminals are short-circuited.

9	Manual evaluation of visual inspection	
Visua	allnsp. Visual inspection Page 1/7	
No со	mment entered!	
~	No damage or contamination	
~	All cables and connectors fulfill the requirements of their intended use	
\checkmark	Condition of the mains plug and the mains connectors and conductors is ok	
~	Visual inspection passed	
×	Visual inspection not passed (sequence is aborted, test failed) Resume test sequence	

Note 🕼

If the plug is disconnected from the test socket during the test sequence, the sequence is immediately disconnected.

Te	st step – start	evalua	tion		
RPE					
R _{PE}	5 m	Ω	wc: lim:	<30	
l _p	232 m A		PE(TS) -	P1	
IP(set)	200 mA ~	Offset		0 m£	Z

Green measured value:

complies with standard





Record measuring point.



Delete last measuring point.



Resume test sequence.

1 Test step – automatic evaluation

IPE NL				4h	
		39	μA	wc: <u>39µA</u> lim: ≤3.50mA	
\mathbf{U}_{LPE}	236.5	۷			
Dif	ferential		Polarity	N/L	

The measured value is ascertained automatically within a specified period of time. The test sequence is then automatically resumed.

Green measured value:

complies with standard



12 Manual evaluation of functions test





Functions test passed



Functions test not passed (sequence is aborted, test failed)



Resume test sequence

Remove DUT from service

Optional test step



(display of the memory screen depends on the parameter pre-selection in the **SETUP** switch position:

Setup 1/3 > Auto. measurements > At end of sequence > Memory screen. If set to events list, (3) is omitted.)

Optional test step



(consideration of measuring error depends on the parameter pre-selection for the **SETUP** switch setting: Setup 1/3 > Auto. measurements > Error considered. > **Yes**)

Optional test step



Optional test step

Confirm re	esults					
Test						
VDE0701-0702		24/09/	2013 01:5	8:24 p	m 🗸	
ShortedCheck L-N					~	<u>_</u> €
Vis. Insp.					\checkmark	<u> </u>
RPE	≤300	mΩ	5	mΩ	\checkmark	
RINS PC I	≥1.00	MΩ	> 300	MΩ	\checkmark	
IPE LN	≤3.50 ▽	mA		μA		\checkmark



Switch to memory screen

17 Save results under ID no.





Save results

or with feature KD01 "Z853S – SECUTEST DB COMFORT":

Send measurement data to the PC, via USB or Bluetooth[®] (Feature M01), e. g. for saving to the **IZYTRONIQ** report generating software (pushprint function), description see online help for **IZYTRONIQ**

11 Measurement Parameters for Individual Measurements and Test Sequences

Measurement parameters which apply for both individual measurements and test sequences, have to be entered in selector switch position **SETUP**.

Meas. Parameter	Meaning
Meas. at IT-mains (Yes / No)	Yes: active leakage current mea- surements (and/or all measure- ments which include the PE at the mains connection end) are blocked. Test sequences which contain such kind of measure- ments are disabled as well.
Ref.voltage L-PE (110 V, 115 V, 220 V, 230 V, 240 V)	The reference (line) voltage is the voltage to which the measured values for leakage current have been standardized. It is used in the case of leakage current for mathematical adjust- ment of the current measuring values to the predefined voltage. Measurements with line volt- age at the test socket: The setting value has no influence on the voltage with which the DUT is supplied via the SECUTEST test socket. Leakage current measure- ments with measurement type "Alternative": The setpoint value of the synthetical test voltage is derived from the value specified here.
Testingfreq Alt	Variable frequency setpoint value
(48 Hz 400 Hz)	 for synthetical test voltage for all leakage current measurements of measurement type "Alternative", affecting the following measure- ments and/or rotary switch posi- tions: Individual measurements (green rotary switch level) Measurements in test se- quences predefined ex factory Measurements in user-defined test sequences (only with database expansion Z853R or feature KB01)

Setup 1/3 > All measurements

12 Repair and Replacement Parts Service Calibration Center and Rental Instrument Service

If required please contact:

GMC-I Service GmbH Service Center Beuthener Straße 41 90471 Nürnberg, Germany Phone: +49 911 817718-0 Fax: +49 911 817718-253 e-mail service@gossenmetrawatt.com www.gmci-service.com

This address is only valid in Germany. Please contact our representatives or subsidiaries for service in other countries.

13 Product Support

If required please contact:

Gossen Metrawatt GmbH				
Product Support Hotline				
Phone,	+49 911 8602-0			
Fax:	+49 911 8602-709			
e-mail:	support@gossenmetrawatt.com			

14 IZYTRONIQ Data Processing Software

IZYTRONIQ is a database test software that has been newly developed from scratch. It enables the user to visualize and manage the entire testing procedure for all our test instruments and to document it in an auditproof manner. For the first time, it is thus possible to combine the test and measurement data from a great variety of test instruments and multimeters in one test and generate one report report thereof. The intuitive user guidance and modern design provide for quick access to all functions.

The software is available in different sizes and versions for trades, industry and vocational training purposes.

Depending on which instrument variant you order, IZYTRONIQ is included in the scope of delivery – for example with standard models and instrument sets (see section 2). If this is not the case or if you would like to take advantage of a variant with a larger scope of functions, you can purchase IZYTRONIQ separately. Detailed information can be found on our website:

www.gmc-instruments.de/en/products/ software-and-accessories/software/



© Gossen Metrawatt GmbH Edited in Germany • Subject to change without notice / Errors excepted • A pdf version is available on the Internet

All trademarks, registered trademarks, logos, product names, and company names are the property of their respective owners.



Gossen Metrawatt GmbH Südwestpark 15 90449 Nürnberg • Germany Phone: +49 911 8602-111 Fax: +49 911 8602-777 e-mail: info@gossenmetrawatt.com www.gossenmetrawatt.com